



Molecular mobility in model heterogeneous cross-linked epoxy networks

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**Du 2 au 7 octobre 2022
À Bussang (Vosges)**

Epoxy networks are an important class of thermoset polymers

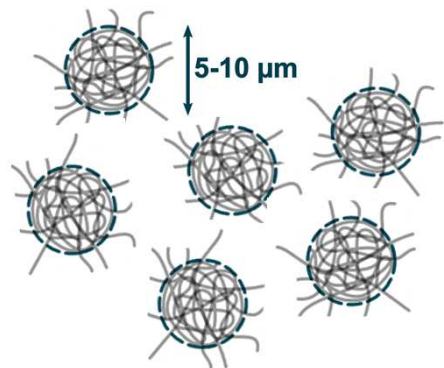
- Drawback for their use as structural materials: **Brittleness**
- **Network structure** is believed to play a crucial role in the **ultimate mechanical properties** of polymers, such as **fracture toughness**

A clear understanding of how **network structure** is correlated with thermosets' **ultimate mechanical properties** is yet to be achieved to enable the **design of polymer materials** with functionalities tailored to specific industrial applications

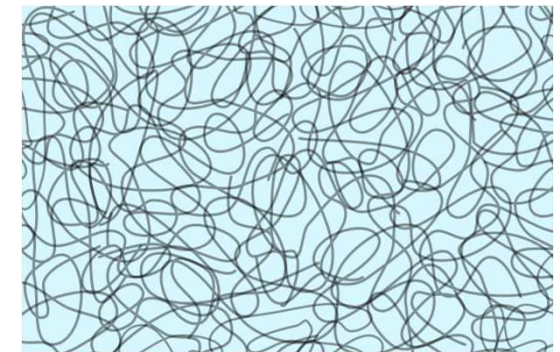
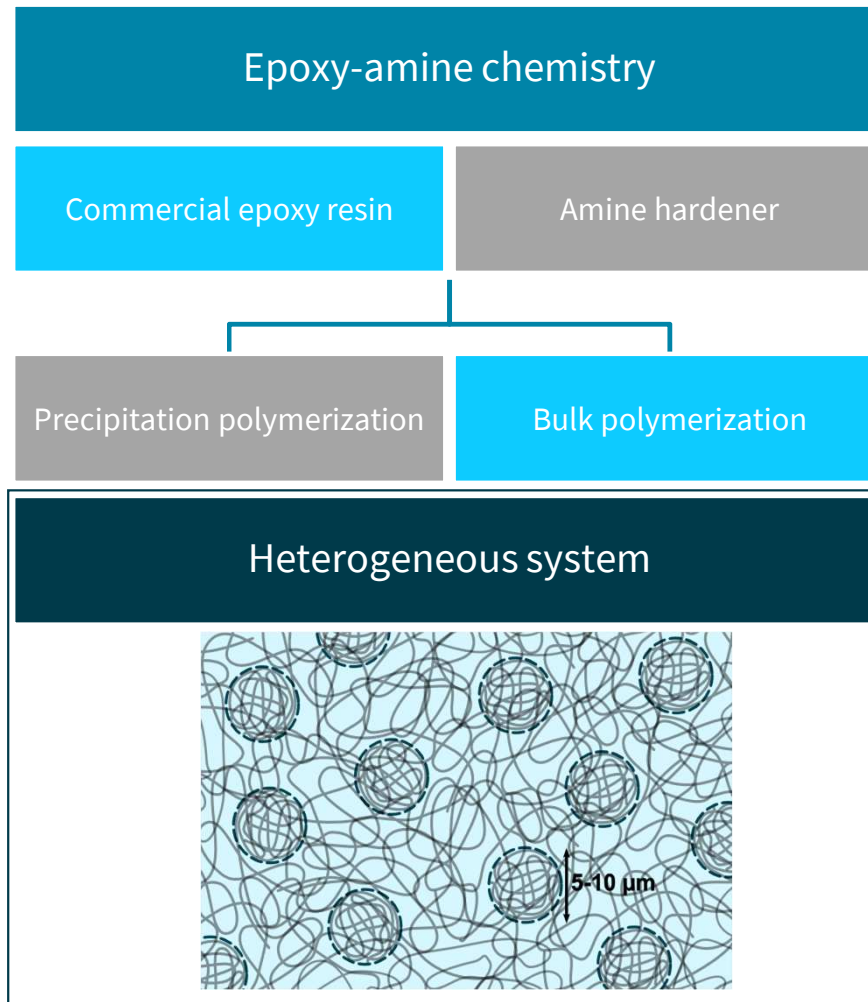
Objective of the project:

- ➔ **To analyze the molecular mobility in polymer systems presenting an increasing degree of heterogeneity.**

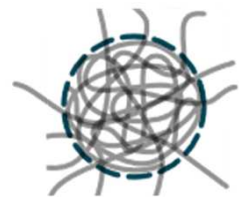
Strategy



Crosslinked **E**poxy **M**icrogels (**CEMs**)



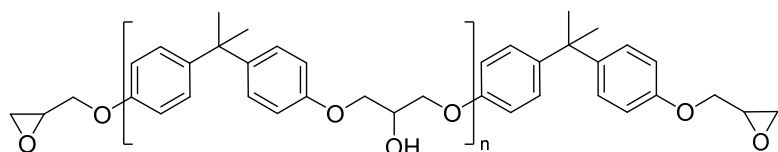
Epoxy matrix



CEMs synthesis

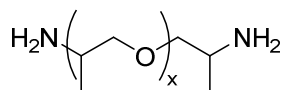
The Crosslinked Epoxy Microgels (CEMs) were synthesized by precipitation polymerization¹

Monomers:



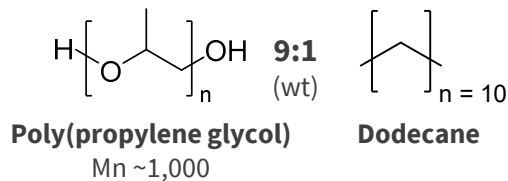
DGEBA
(EEW = 183 - 192 g/eq, $n \sim 0.12$)

+

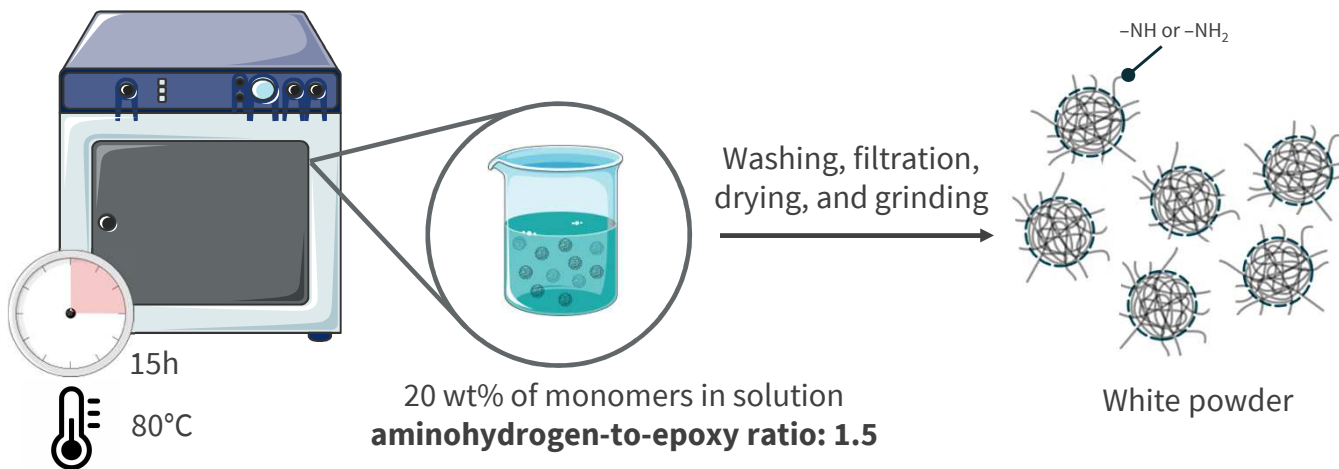


Jeffamine
(D230, $x \sim 2.5$)

Solvent:



Precipitation polymerization protocol:



Characterization:

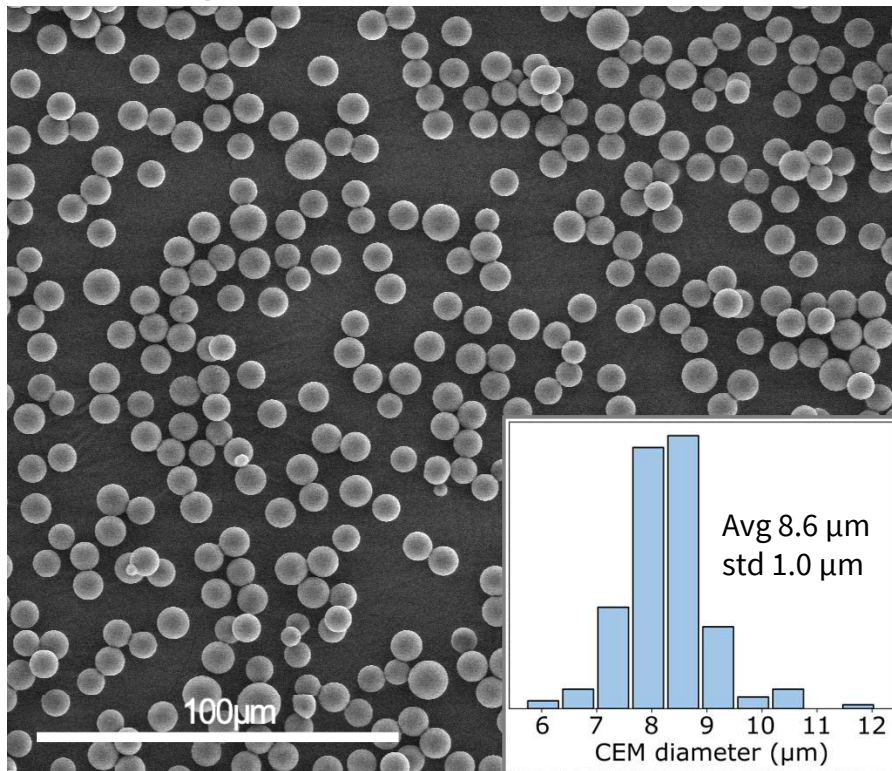
- DSC
- TGA
- IR
- SEM
- Helium pycnometry

Optimized to obtain **narrow size distribution**

1. M.L. Michon, INSA Lyon PhD, 2014.

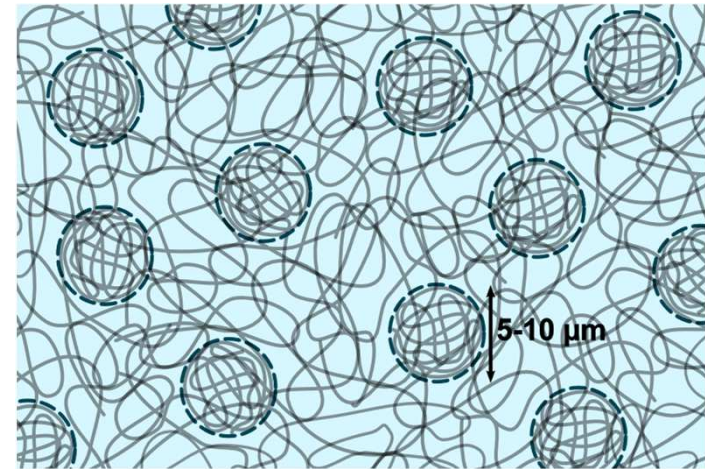
CEMs obtained have narrow size distribution

SEM micrographs of model CEMs:



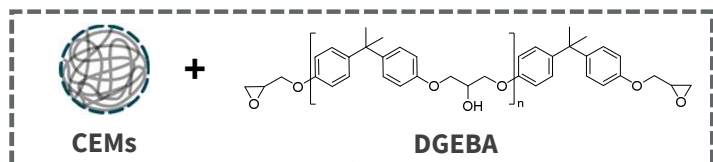
- **TGA** Solvent removal during washing protocol was confirmed
- **IR** The presence of remaining primary and secondary amine functional groups was confirmed
- **Pycnometry** Average density of CEMs : 1.18 g/cm³
- **DSC** T_g 1st run: 67 °C
 T_g 2nd run: 70°C

Obtention of the heterogeneous system



The CEMs were dispersed in DGEBA and cured using D230 as hardener

1 Masterbatch (MB) preparation:



Mechanical dispersion
Ultra-Turrax
(11k rpm)



Dispersion cycles



Dispersion control
with optical
microscopy

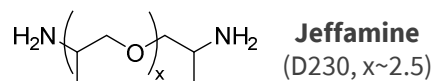
Sonication



Temperature control < 55°C



2 MB dilution in DGEBA followed by hardener addition

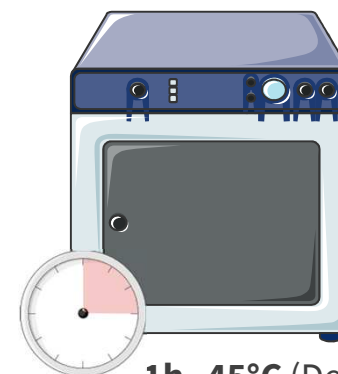


Homogenization using Vacuum speedmixer

30min
800 – 2000 rpm
30 mbar



3 Curing in vacuum oven

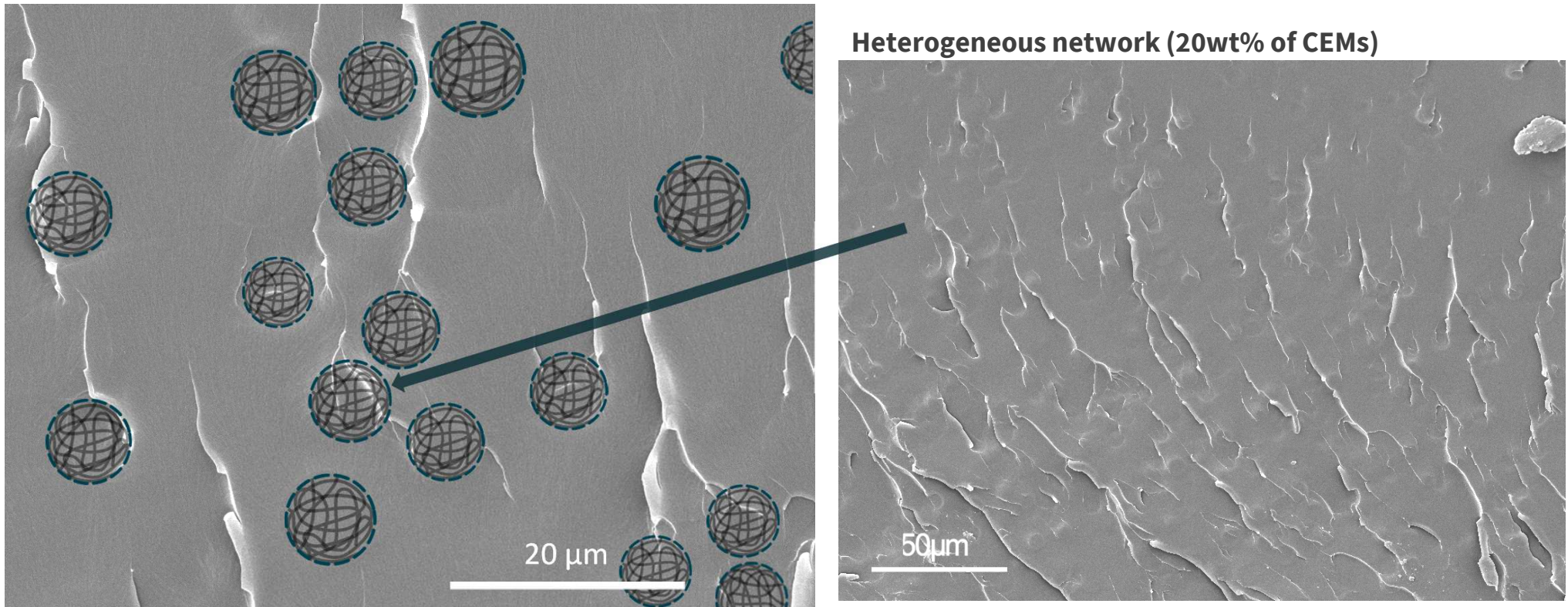


1h 45°C (Degassing step)
2h 80°C¹
3h 125°C
1h 200°C

The networks were obtained as **thin films (~500µm)** with **homogeneous thickness**; the **reference matrix film** (DGEBA/Diamine, a/e = 1) was synthesized using the same curing protocol.

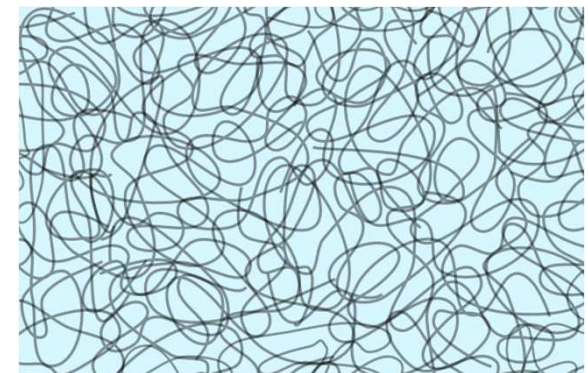
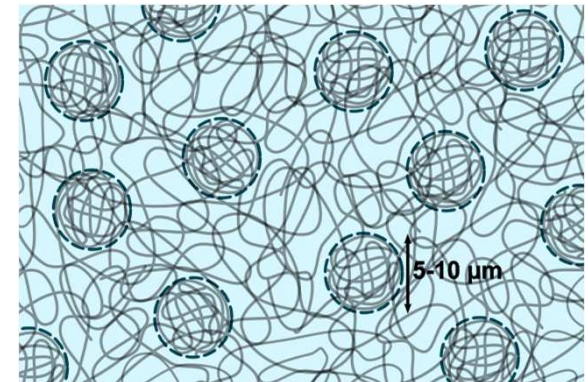
1. Nguyen, T. K. L., Livi, S., Soares, B. G., Pruvost, S., Duchet-Rumeau, J., & Gérard, J. F. (2016). Ionic liquids: A new route for the design of epoxy networks. ACS Sustainable Chemistry & Engineering

SEM micrographs of cryogenic fracture surface of fully cured networks

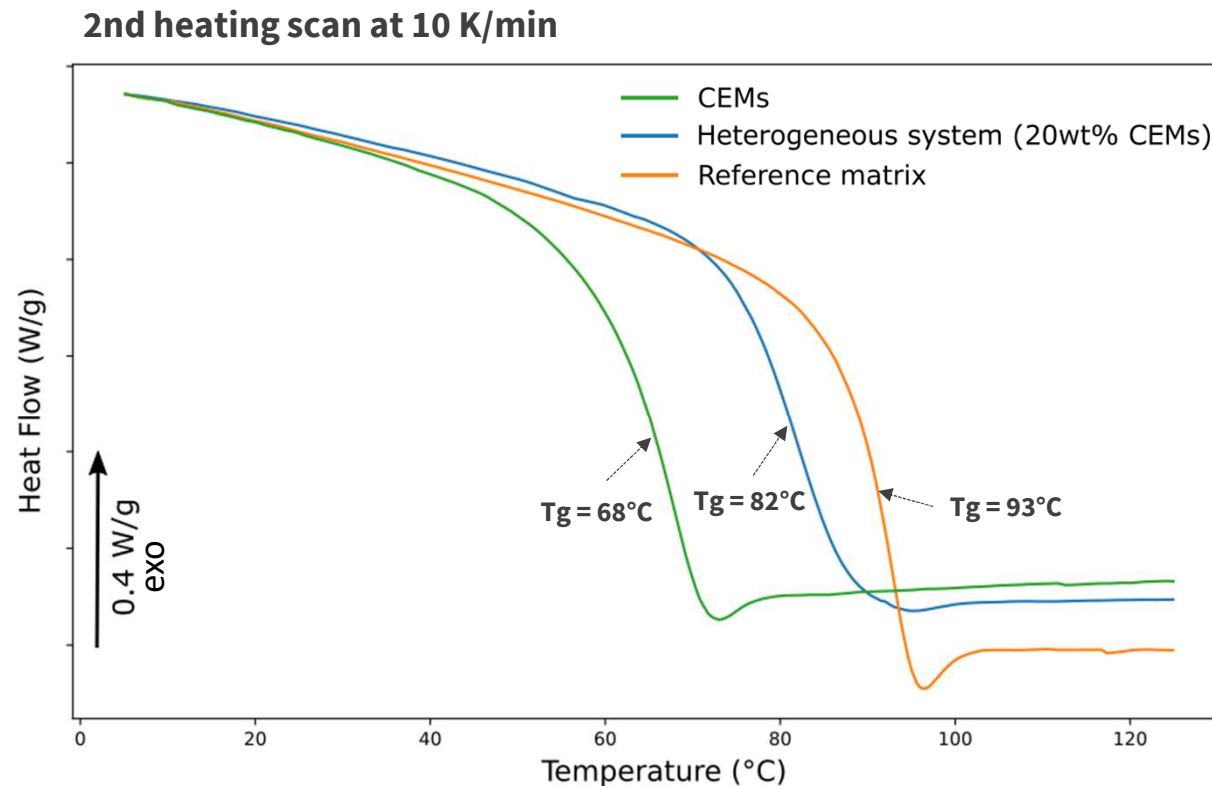


- **Strong adhesion** suggests that **CEMs** could be **covalently bonded** to the matrix.

Analysis of molecular mobility of the heterogeneous system compared to reference matrix



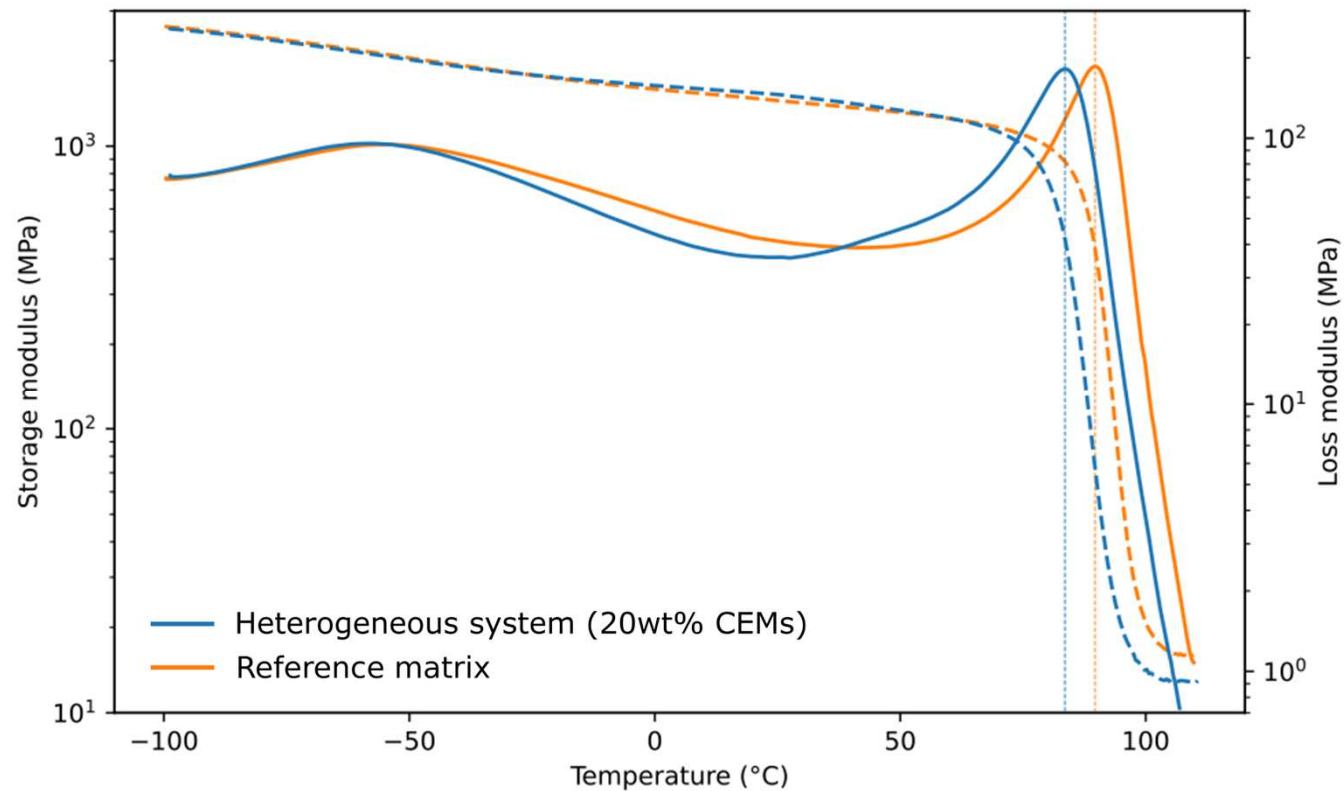
DSC of the heterogeneous system compared to reference film and CEMs



- Only **one single glass transition temperature** is observed for the heterogeneous system, behaving like a **homogeneous system** despite the **heterogeneity in SEM analysis**

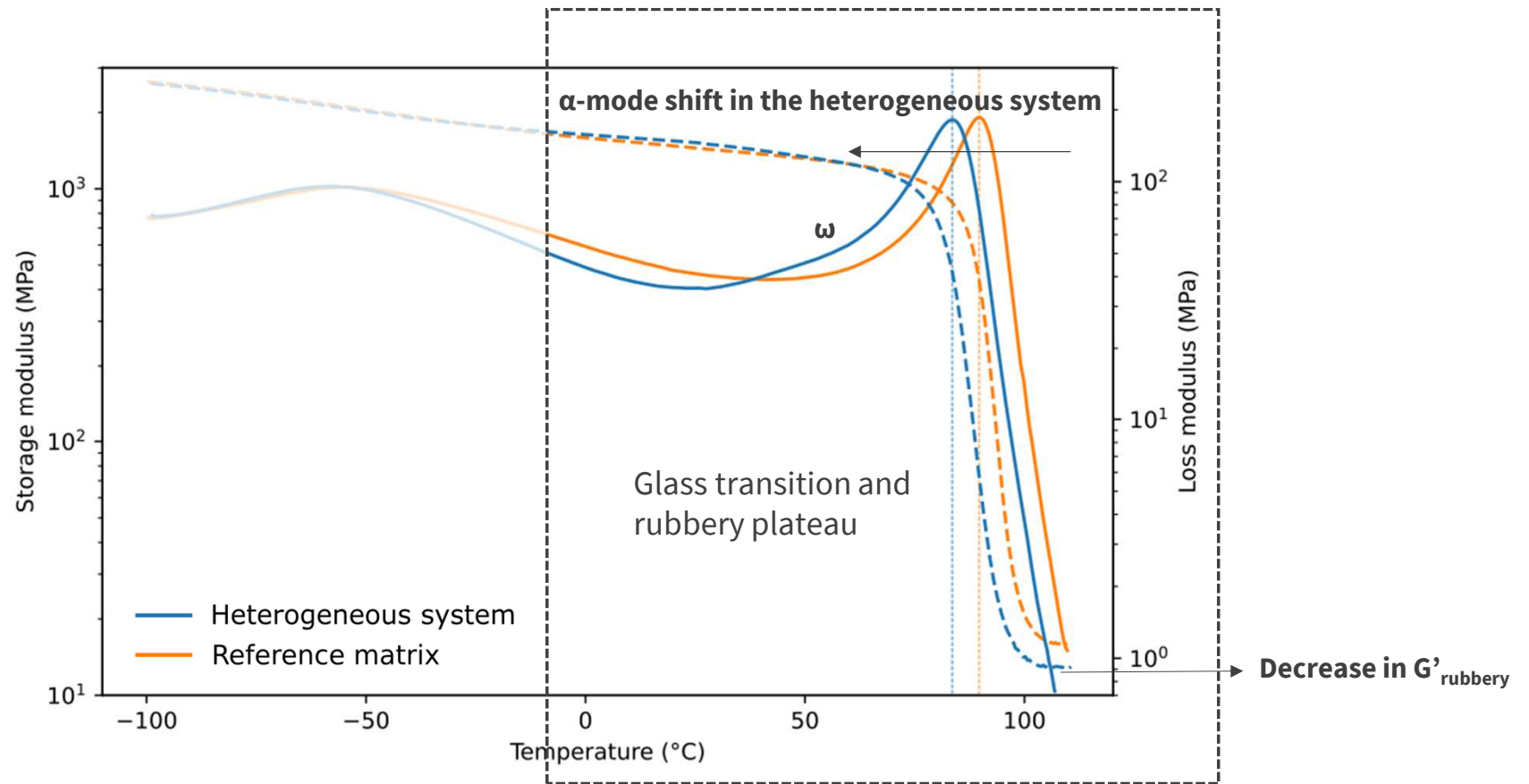
DMA characterization of the heterogeneous system and reference matrix

- DMA storage and loss modulus curves obtained by **retangular torsion mode** at **1 Hz**, **3 K/min** and **0.05% strain** (2nd heating ramp)



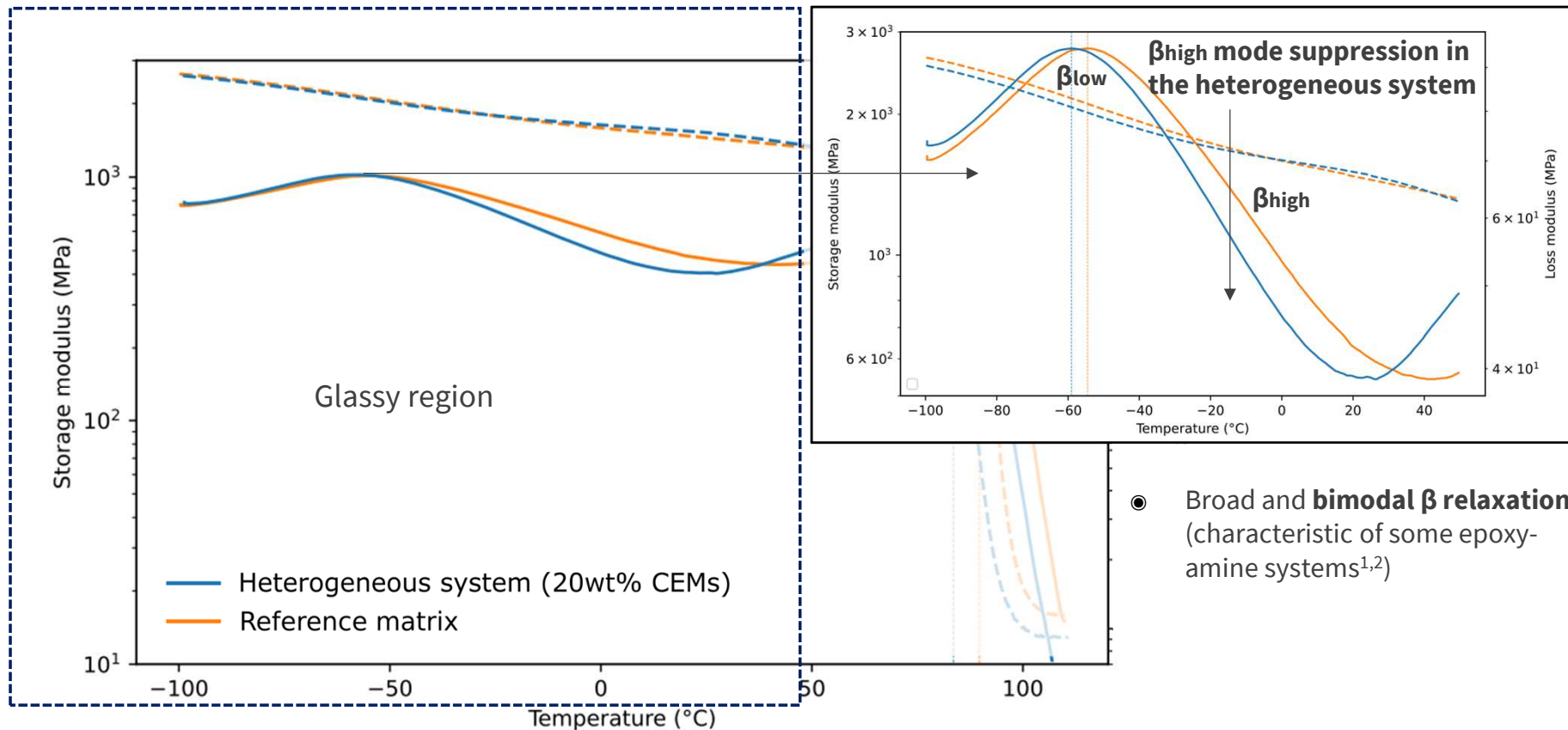
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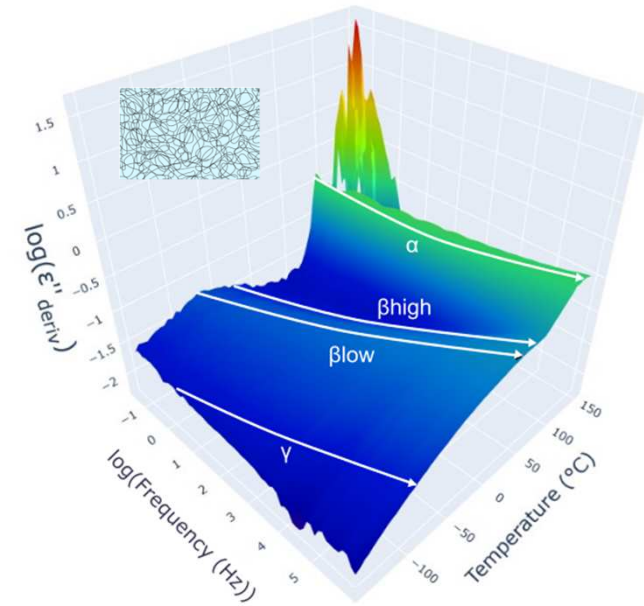


- Broad and **bimodal β relaxation** (characteristic of some epoxy-amine systems^{1,2})

1. Won, Y. G. et al. (1990). Internal antiplasticization in copolymer and terpolymer networks based on diepoxides, diamines and monoamines. *Polymer*, 31(9), 1787-1792.

2. Ramsdale-Capper, R. et al. (2018). Internal antiplasticisation in highly crosslinked amine cured multifunctional epoxy resins. *Polymer*, 146, 321-330.

Dielectric relaxation map of the reference sample



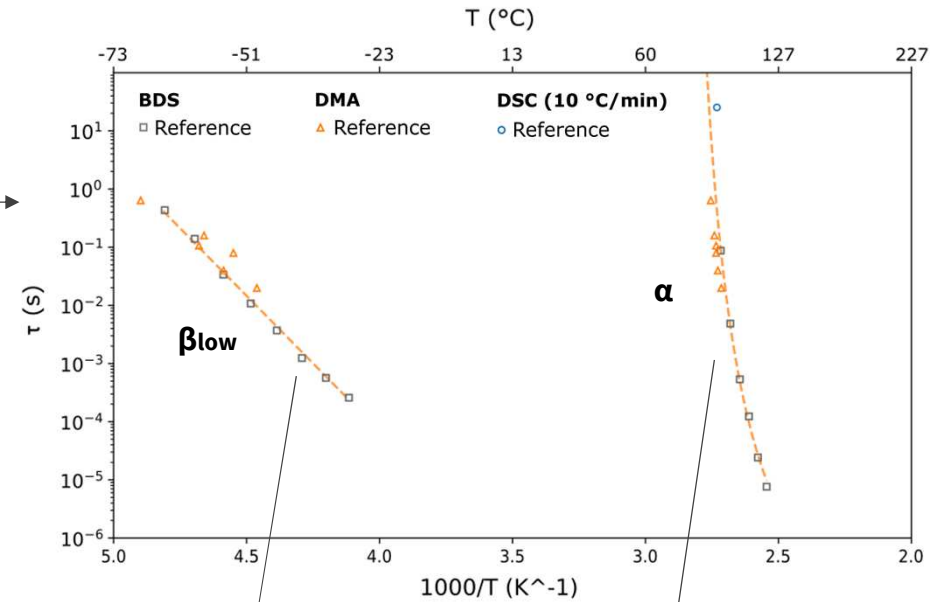
Fitted using Havriliak-Negami equation

$$\epsilon^* = \epsilon'_{\infty} + \frac{\epsilon'_s - \epsilon'_{\infty}}{(1 + (i\omega\tau_{H-N})^{\alpha_{H-N}})^{\beta_{H-N}}}$$

- DSC equivalent frequency was determined using¹:

$$f_{eq} = \frac{q}{2\pi\alpha\delta T}$$

- Good agreement between DSC, DMA, and BDS data.



Arrhenius behavior of β -relaxation

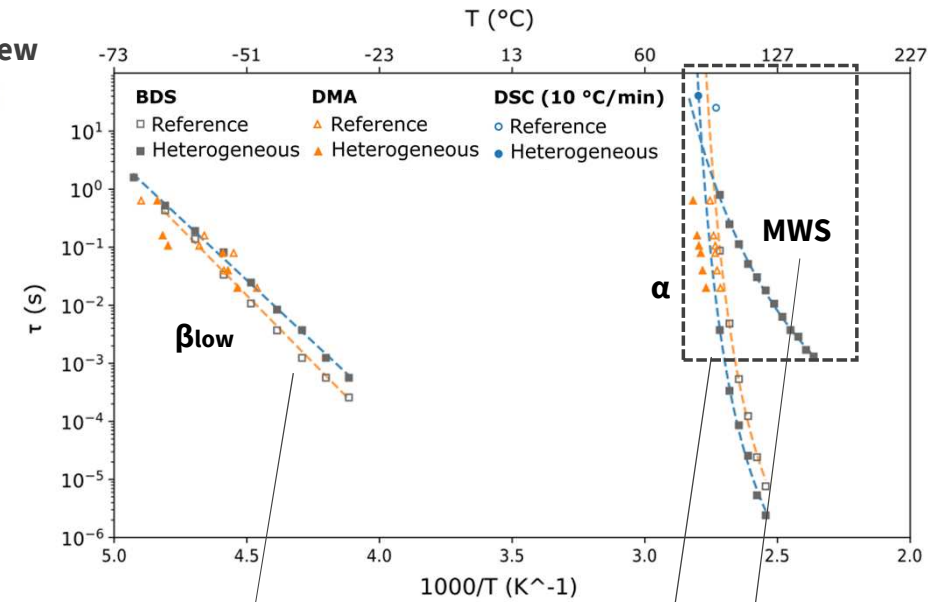
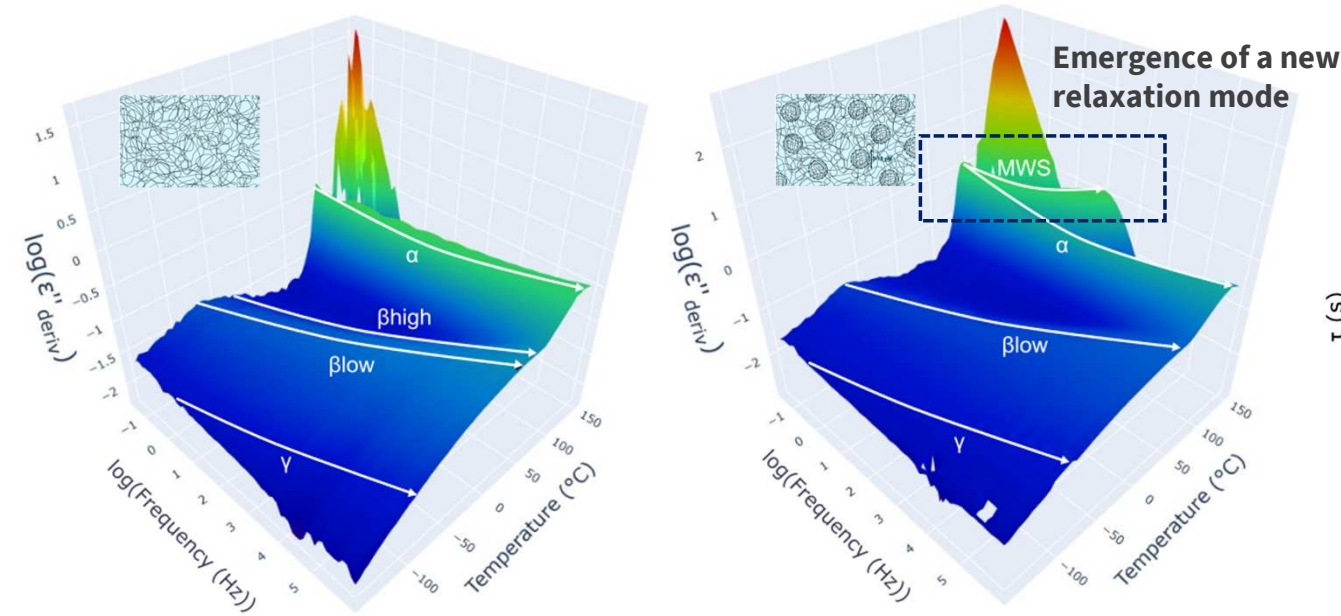
$$\tau^{Arr}(T) = \tau_0 e^{\frac{E_a}{RT}}$$

Vogel-Fulcher-Tammann behavior of α -relaxation

$$\tau^{VFT}(T) = \tau_0 e^{\frac{1}{\alpha_f(T-T_{\infty})}}$$

1. Donth, E.-J. Relaxation and Thermodynamics in Polymers: Glass Transition; Akademie Verlag: Berlin,1994.

Dielectric relaxation map of the heterogeneous network sample

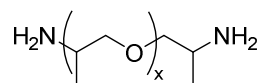


- The additional relaxation mode appears only in BDS measurement, thus **no mechanical response** of the responsible entities;
- Could be ascribed to macrodipoles formed by **interfacial polarization** or Maxwell–Wagner–Sillars (**MWS**)

Result of conductivity heterogeneity in the network

Isofrequency comparison between DMA and BDS measurements

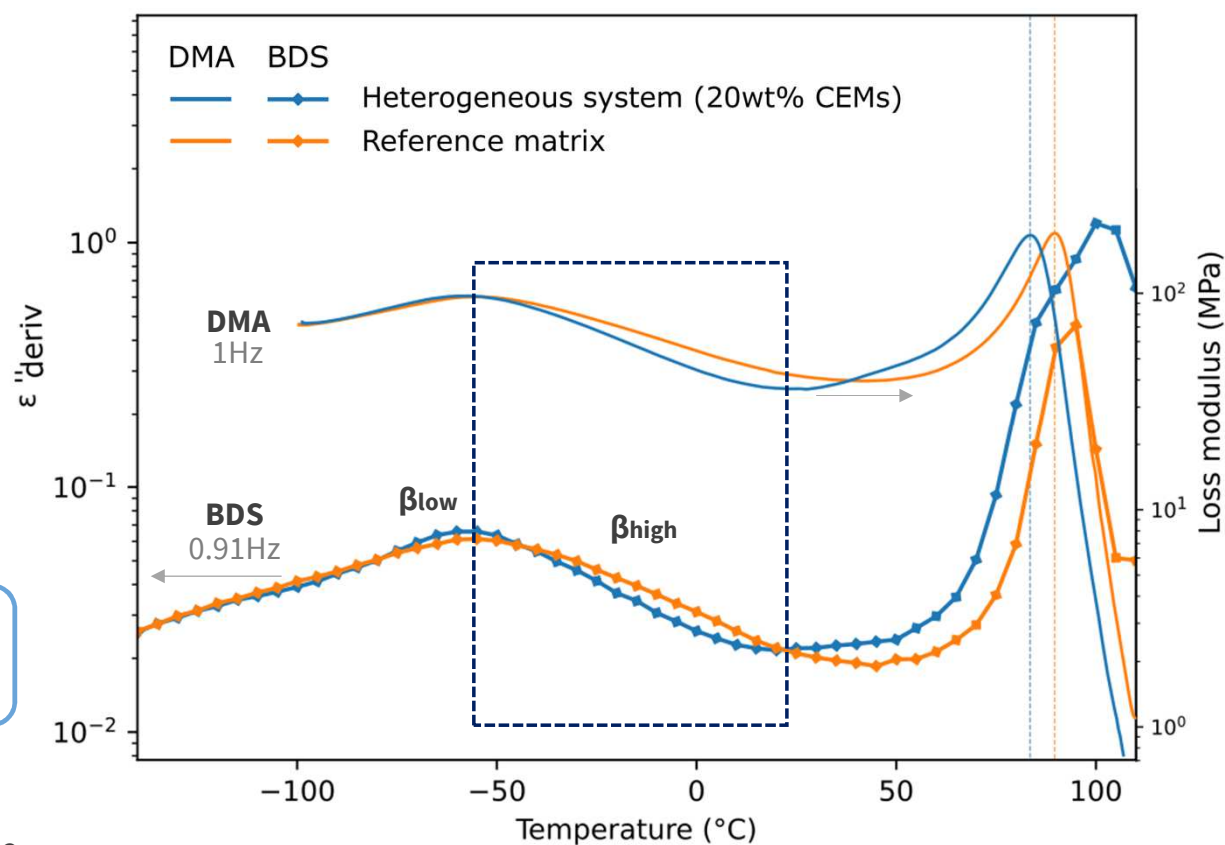
- β -relaxation ascribed to the **localized mobility of hydroxyether units** and/or **phenyl ring flips**
- β_{high} was associated with **phenyl ring flips** in the **hardener parts** of the network¹



No phenylene rings
in the hardener

- β_{high} supression is **commonly observed** in systems containing structure modification leading to a **lower network crosslink density**²

Would CEMs' addition to the network result in lower average cross-linking density of the material?



→ **Complementary analysis** to understand the origin of this **restriction in molecular mobility** needs to be done.

1. Ramsdale-Capper, R., & Foreman, J. P. (2018). Internal antiplasticisation in highly crosslinked amine cured multifunctional epoxy resins. *Polymer*, 146, 321-330.

2. Won, Y. G., Galy, J., Gérard, J. F., Pascault, J. P., Bellenger, V., & Verdu, J. (1990). Internal antiplasticization in copolymer and terpolymer networks based on diepoxides, diamines and monoamines. *Polymer*, 31(9), 1787-1792.

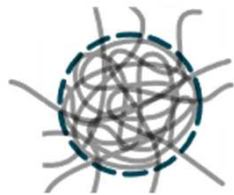
Conclusion and perspectives

Conclusions

- The obtained results show an impact of the presence of CEMs on both the α and β modes of the epoxy matrix;
- The single T_g suggests **homogeneous-like behavior** of the heterogeneous system;
- Meanwhile, **interfacial polarization** observed in BDS measurement suggests **phase heterogeneity** in the heterogeneous system, aligned with SEM observation;
- **β high mode suppression** in the heterogeneous system seems to be **due to CEMs'** presence in the matrix. The mechanism generating this **mobility restriction** needs to be elucidated.

Perspectives

- Finalize **the interpretation of the relaxation modes** in the reference and heterogeneous networks;
- Replicate the study using **different hardeners in the matrix** (e.g. D400 and D2000) to change crosslink density and thus the **contrast between matrix and CEMs**;
- Vary **the fraction of dispersed CEMs** to study the influence of the **heterogeneity degree** on molecular mobility;
- **Network topology** visualization using **AFM**;
- Study the **networks' fracture behavior** (e.g. determine fracture toughness or solvent crack behavior);



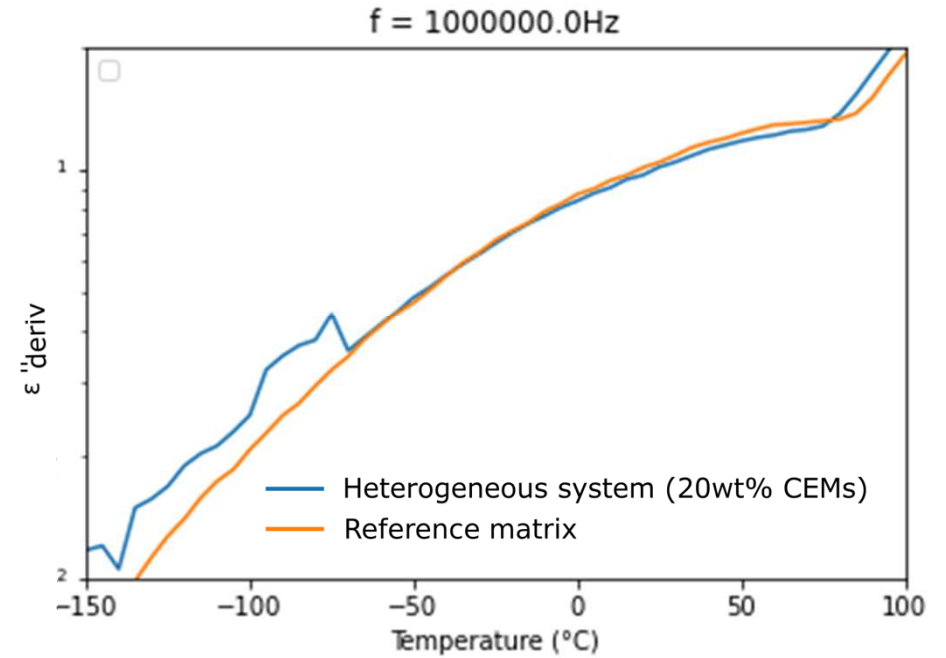
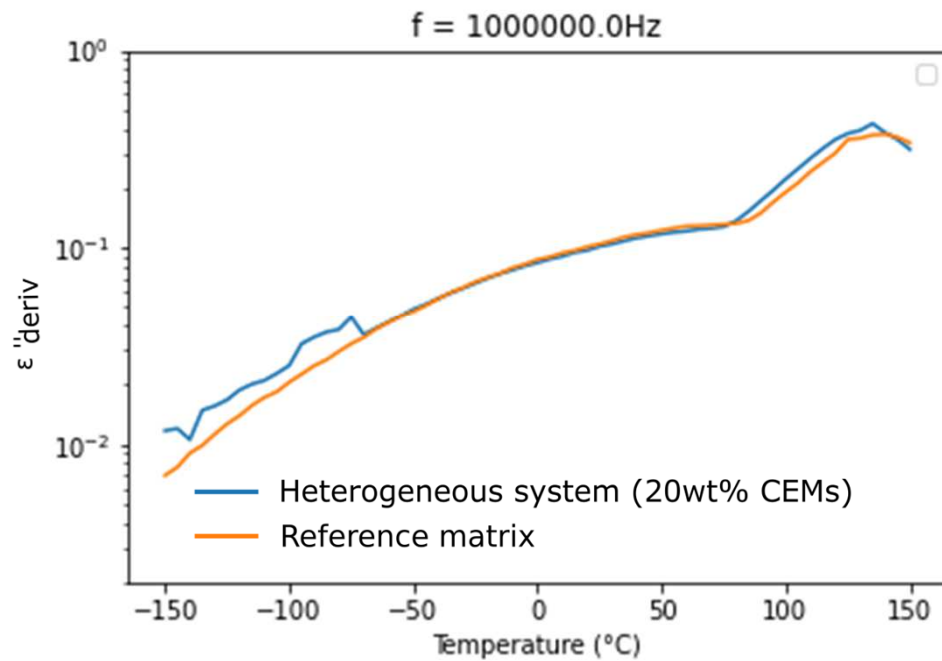
**Thank you for your
attention**

Annexes

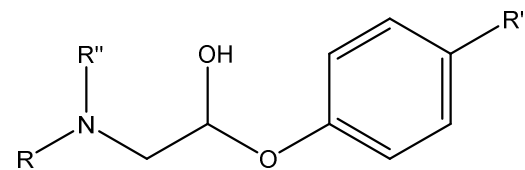
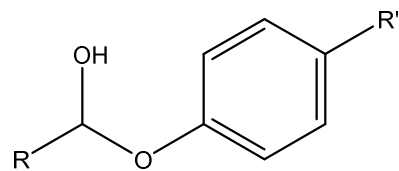
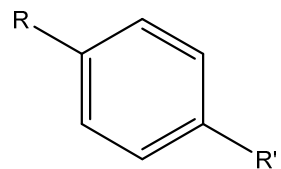
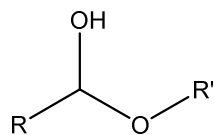
Other perspectives

- Characterize the films by **IR/NIR**, **solvent swelling**, and **pycnometry** to gain more information about the crosslink density;
- Follow the **network build-up** of reference and heterogeneous system by **IR and DSC** to gain information on CEMs' influence on **curing kinetics**
- **Solid NMR** to gain more information about chemical environment of the entities

Beta relaxation mode shift with increasing frequency



- **hydroxyether** units and/or **phenyl ring** flips

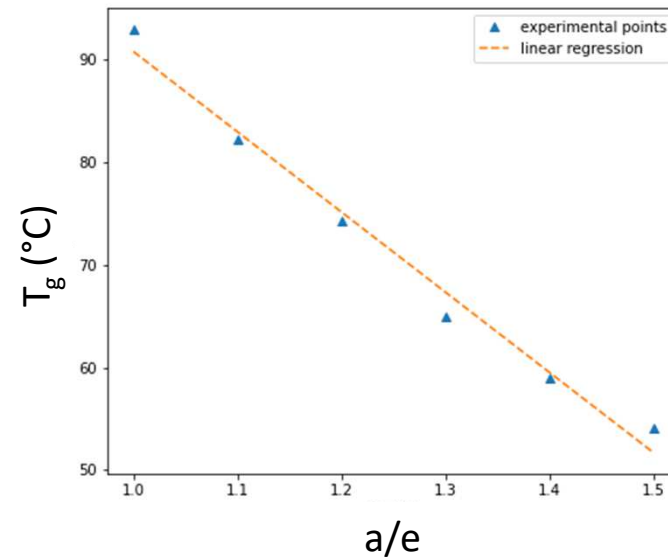


- **Eps deriv definition**

$$\varepsilon''_{\text{der}} = -\frac{\pi}{2} \frac{\partial \varepsilon'(\omega)}{\partial \ln \omega} \approx \varepsilon''_{\text{rel}}$$

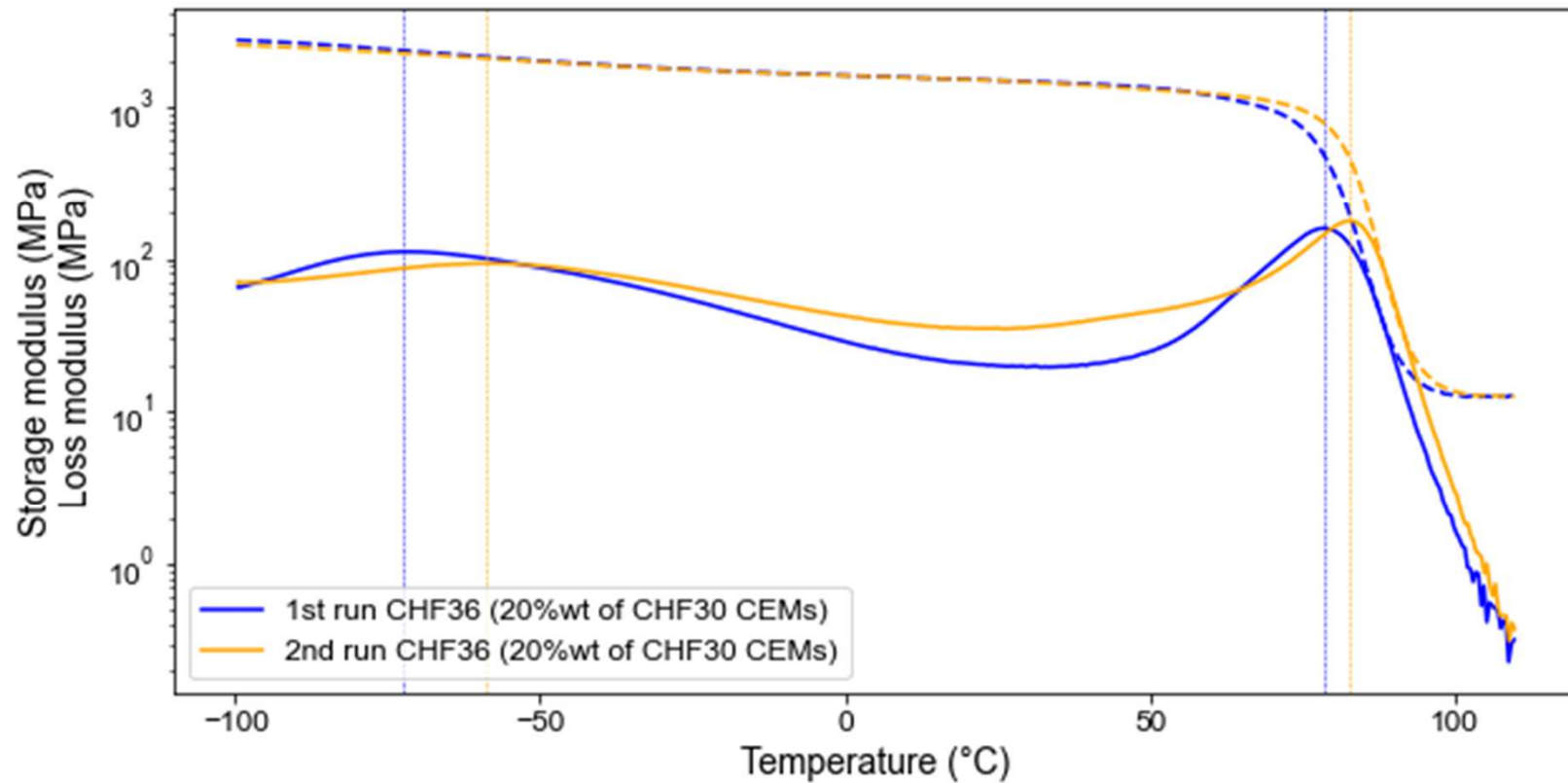
- “conduction-free” imaginary part, ε'' deriv (that is not entirely true because **ionic conductivity** and **electrode polarization** also contribute to ε' ,

CEMs' final aminohydrogen-to-epoxy ratio estimate

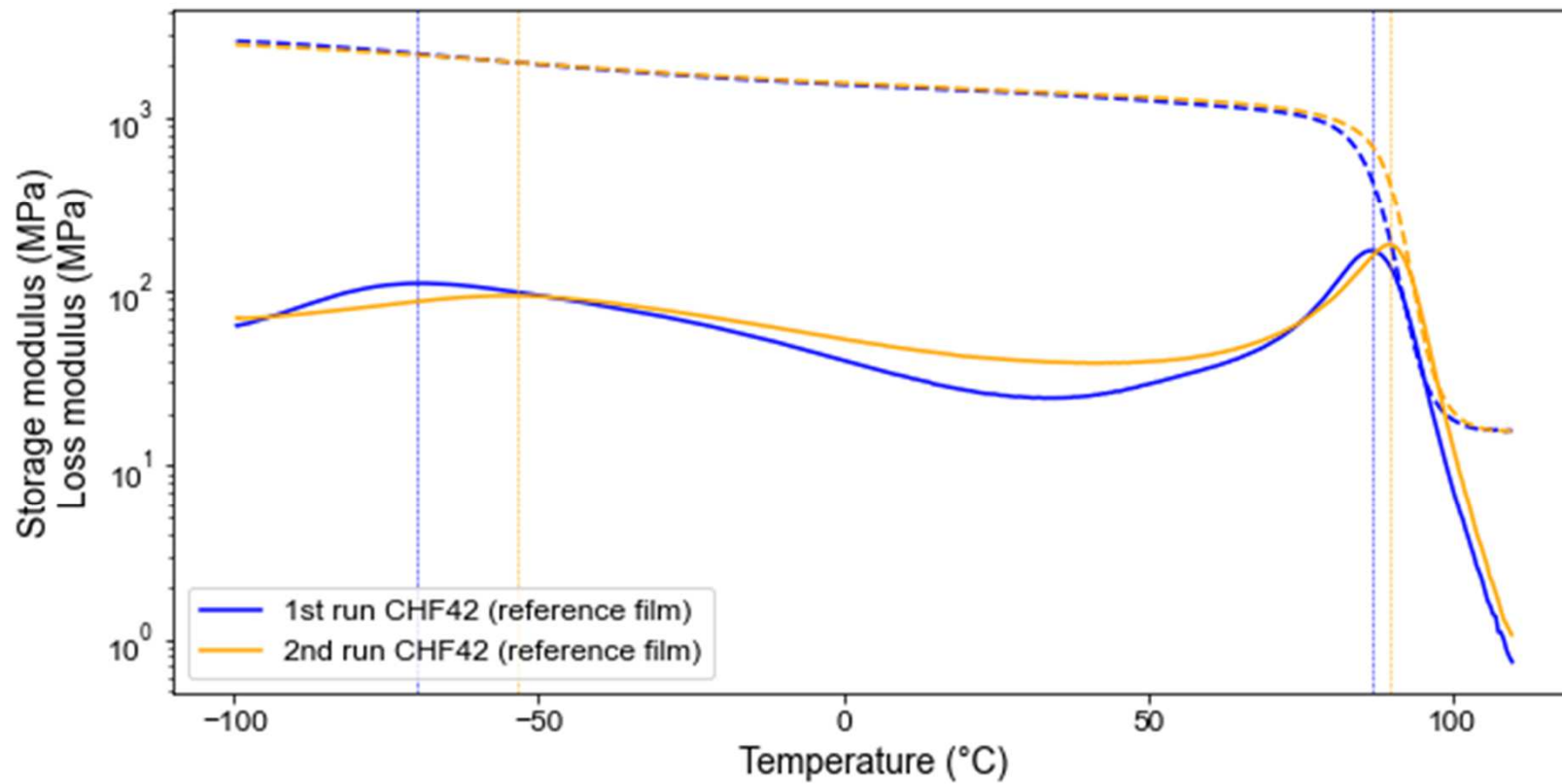


- Equivalent stoichiometric ratio of microgels calculated from T_g

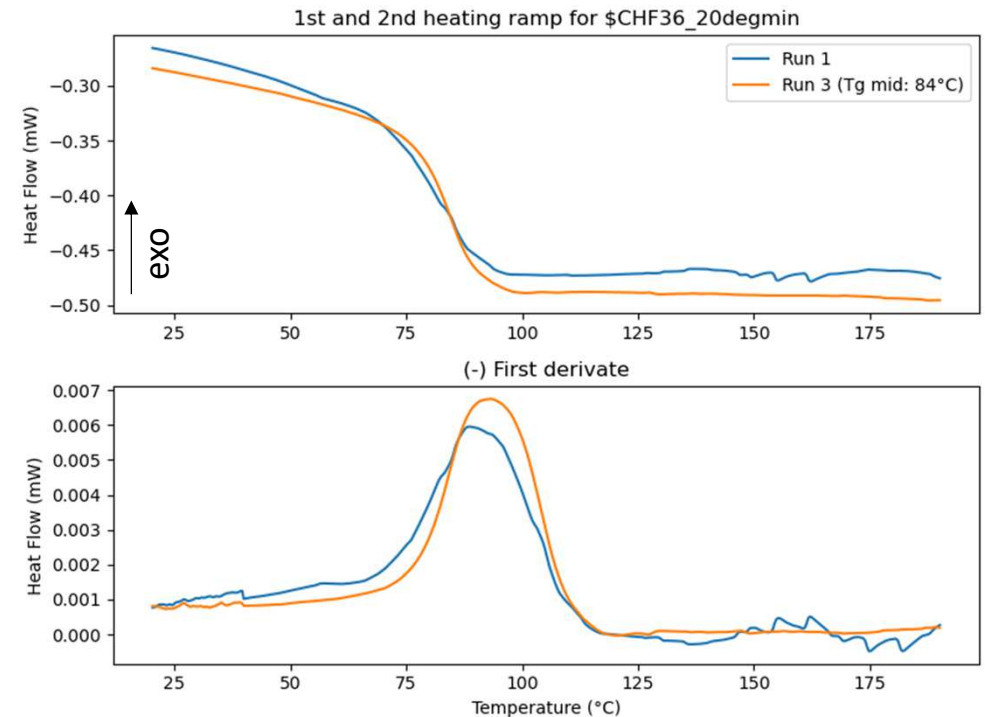
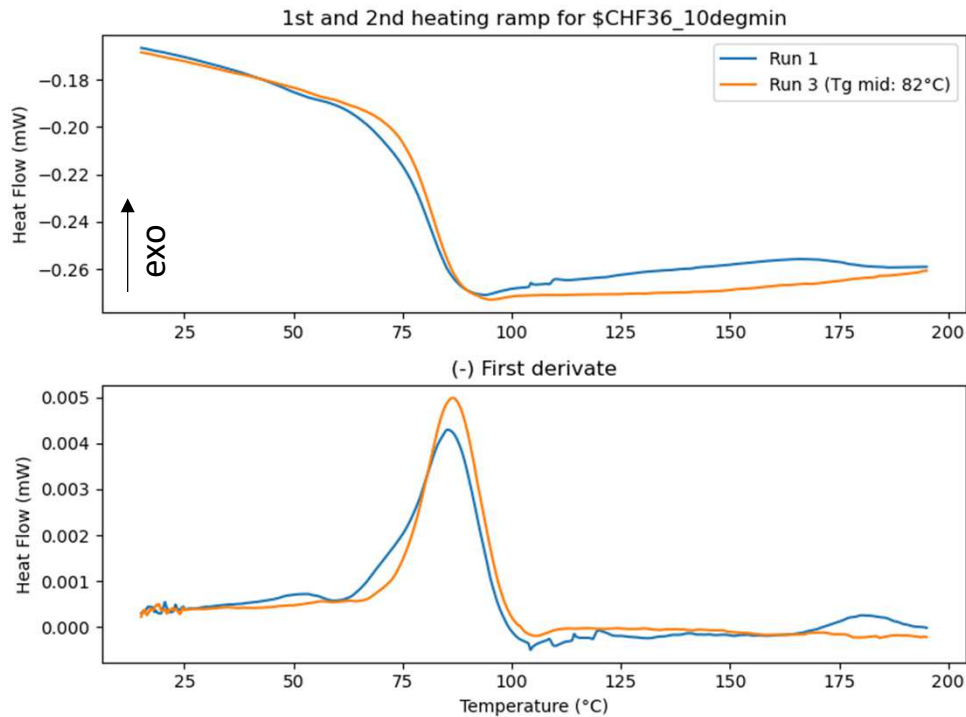
DMA first and second run: Heterogeneous system film



DMA first and second run: Reference film

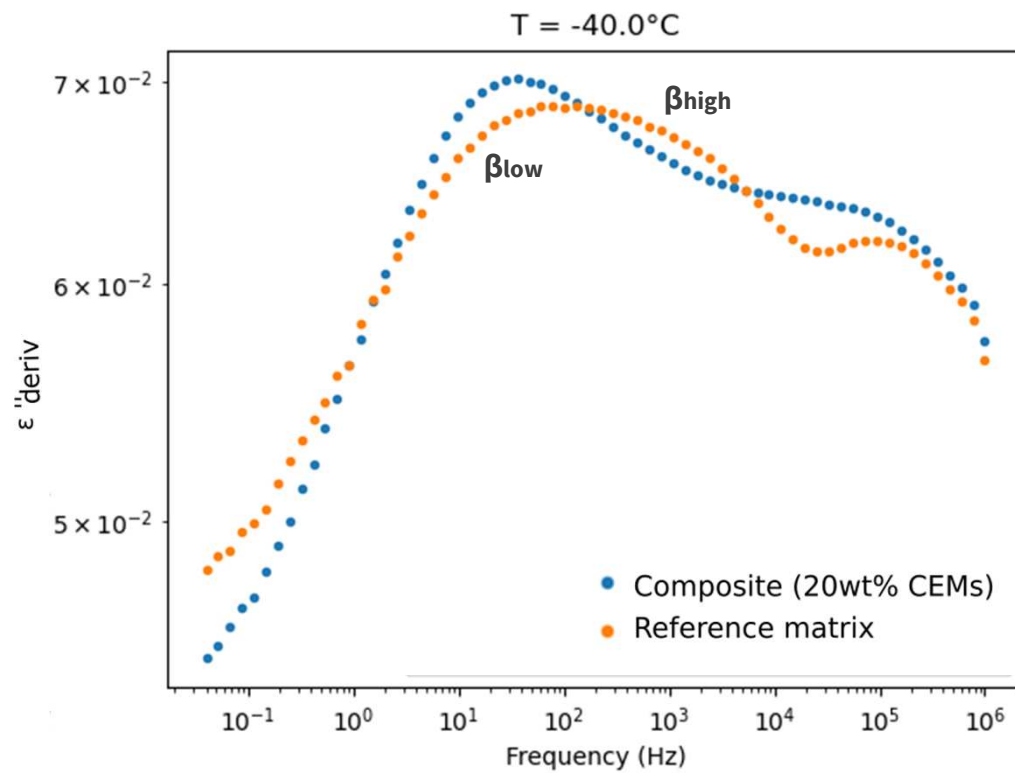


DSC heterogeneous system (20wt% CEMs): 10 and 20 K/min

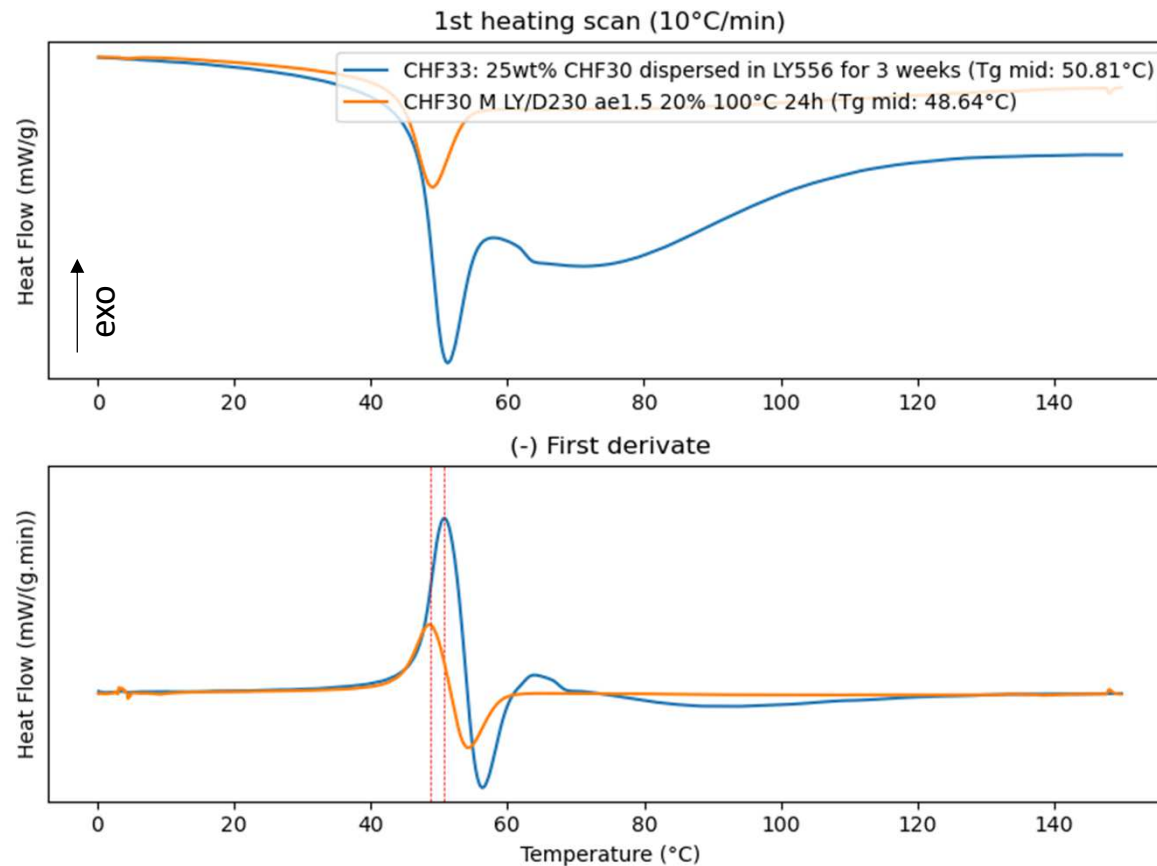


- Single T_g observed despite of the heating rate.

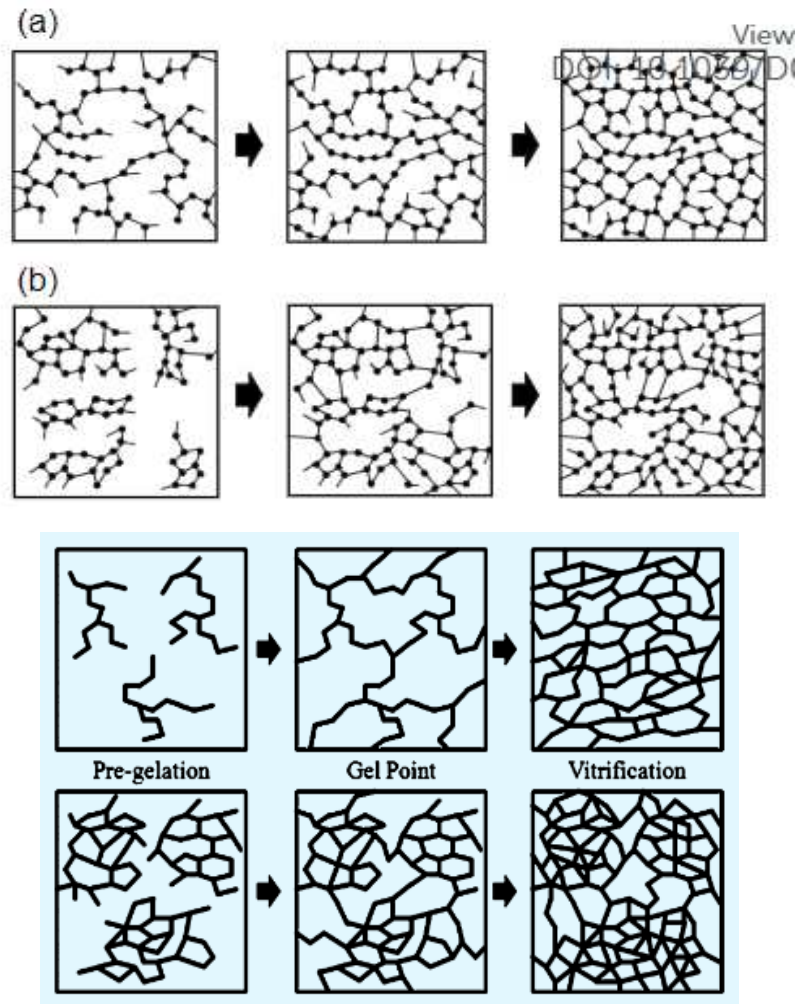
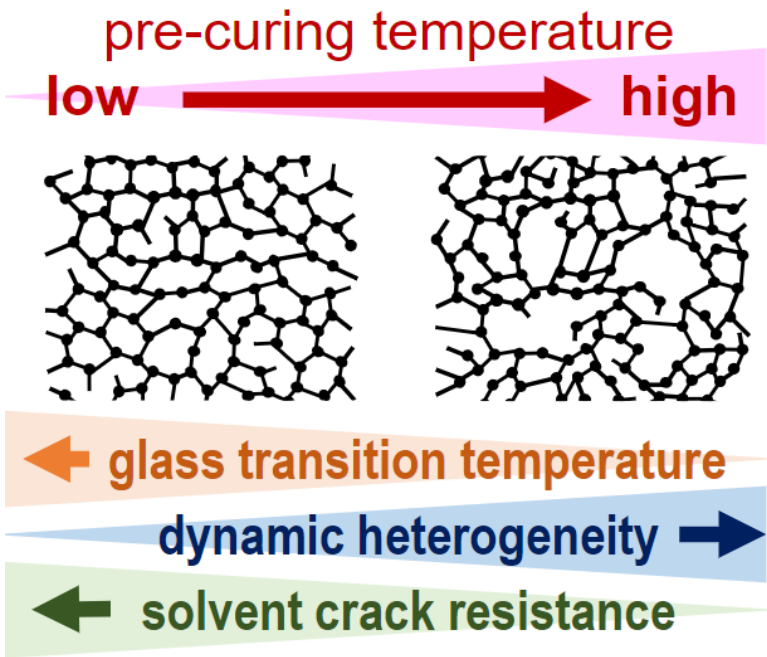
Isotherm comparison between DMA and BDS measurements



DMA characterization of reference and heterogeneous system systems



- CEMs T_g remains the same when embedded in DGEBA for 3 weeks, indicating no significant diffusion of the resin into CEMs core at masterbatch storage conditions



1. Aoki, M., Shundo, A., Yamamoto, S., & Tanaka, K. (2020). Effect of a heterogeneous network on glass transition dynamics and solvent crack behavior of epoxy resins. *Soft Matter*, 16(32), 7470-7478.
2. Sahagun, C. M., & Morgan, S. E. (2012). Thermal control of nanostructure and molecular network development in epoxy-amine thermosets. *ACS applied materials & interfaces*, 4(2), 564-572.